Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10020030	MYERS, STEVEN DUANE	
Examiner	Art Unit	
Nguyen-Ba, Hoang-Vu A	2623	

SEARCHED				
Class	Subclass	Date	Examine	

SEARCH NOTES				
Search Notes	Date	Examiner		
East Search USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	3/15/07	HAN		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examine	